ON Semiconductor

Update Notification
Generic Copy

15-MAR-2005

SUBJECT: ON Semiconductor Update Notification #13954

TITLE: Update Notification to PCN #12837 Final PCN for Qualification of Analog 8 LEAD PDIP Products at AIT

EFFECTIVE DATE: 15-May-2005

AFFECTED CHANGE CATEGORY(S)
Subcontractor Assembly/Test Site

AFFECTED PRODUCT DIVISION: Analog Products

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact your local ON Semiconductor sales office

NOTIFICATION TYPE:
Initial Product/Process Change Notification (IPCN) -
First Notification distributed to customers. Distributed at least 120 days from the effective date of the change.

Final Product/Process Change Notification (FPCN) -
Final Notification completing the notification process. Distributed at least 60 days from the effective date of the change. ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:
This is an Update to FPCN 12837. The devices below were excluded from the original FPCN to allow for a complete assembly evaluation.

This is a Final Product Change Notice to make customers aware that Advanced Interconnect Technology (AIT), located in Batam, Indonesia is being qualified as a supplemental manufacturing source for ON Semiconductor's Analog 8 lead PDIP products. An Initial PCN (#12837) was published on 16 April 2003 providing information on all the devices being transferred and the scope of this program.

AIT is QS9000 and ISO9002 certified, and has been a qualified subcontractor for ON Semiconductor devices since 1990. AIT is the primary supplier to ON Semiconductor for Analog 14/16 lead PDIP products. The Analog 8 lead PDIP package has been qualified to run specific devices that are currently processed at ASE's Penang, Malaysia location. This is not a transfer but a capacity expansion.

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Device parameters will continue to meet all Data Book specifications, and reliability will continue to meet or exceed ON Semiconductor standards. At the expiration of this PCN, the devices listed below may be processed at either manufacturing location depending on capacity and demand requirements.

RELIABILITY DATA SUMMARY:

Reliability testing was performed on 3 lots of the LM2574N-5 device. This device was selected because it represents the largest die size of the devices that will be affected by this expansion.

Reliability tests included:

Test	Conditions	Interval
Autoclave	Ta=121DegC, RH=100%	96 hrs, 3 lots, 240 units
HAST	130C/85% RH	96 hrs, 3 lots, 240 units
Temp Cycling	Ta=-65 deg C to +150 deg C	500 cyc, 3 lots, 240 units

Autoclave

Lot ID	Read Point - 96 hours
A	0/80
B	0/80
C	0/80

HAST

Lot ID	Read Point - 96 hours
A	0/80
B	0/80
C	0/80

Temperature Cycling

Lot ID	Read Point - 500 cycles
A	0/80
B	0/80
C	0/80

ELECTRICAL CHARACTERISTIC SUMMARY:

Electrical data will remain unchanged and is available on request.

AFFECTED DEVICE LIST(WITHOUT SPECIALS):

PART

TCA0372BDP1

TCA0372DP1